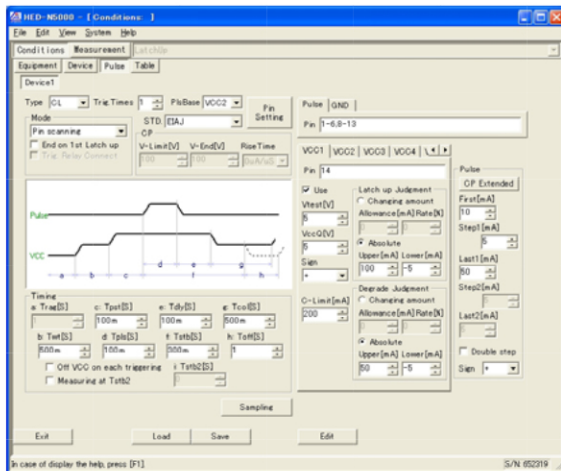


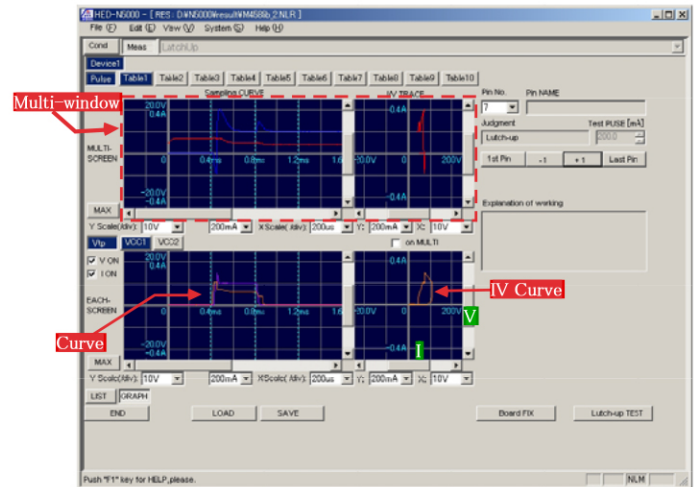
■ Latch-up test and result of measurement

Setting of Latch-up test



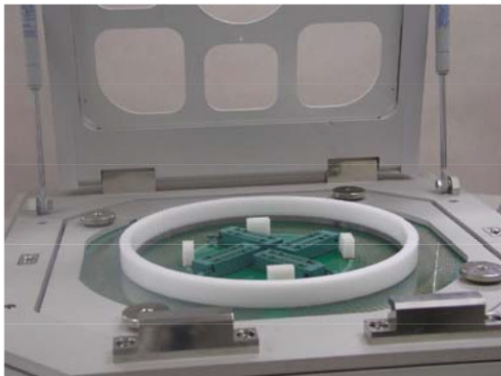
The setting for the timing of inserting pulse or the time width with confirming the visual figure is possible.

Result of test



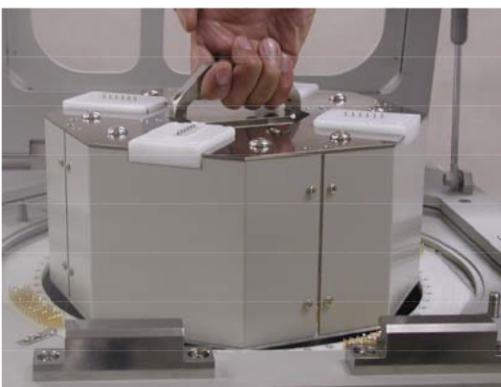
Visual confirming of pulse value that was input in practice and the position that Latch-up was occurred is possible.

Socket Board and Zap unit



Socket board

- Max. 8 sockets can be installed, and simultaneous zapping to each socket (these needs to discuss) is possible. Simultaneous zapping makes test time shorter.
- Making of socket board that adaptable to every package is possible.



Zap unit

- Zap unit can be put and removed easily with desorption method.
- Machine Model (MM) × 2 and Human Body Model(HBM) × 2 are featured as standard. Making zap unit as your option request is possible.

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● Agency

Automatic ESD Test System

HED-N5000 series



Our original mechanical system has made possible for this equipment to test the device of Max. 1024 pins. The equipment occupies small space and it is approximately same size as conventional equipment that is for small pin. The test function corresponds with electrostatic test and Latch-up test, which meet the latest standard, and friendly operation provides high precise test.

Features

■ Simultaneous plural zapping is practicable

Installing Max. 8 sockets and simultaneous plural zapping into each socket are possible.

■ Effective use of existing asset

Socket board, which is equipped with conventional ESD test instrument, is usable.
(HED-S5000 series, HED-F5000series)

■ Adaptable to various standard waveforms

This corresponds with domestic and abroad standard such as JEITA standards, JEDEC standards and ESDA standards.

■ Adaptable to Latch-up test

This corresponds with ESD pulse zapping method, V_{supply} over-voltage zapping method and constant current pulse zapping method.

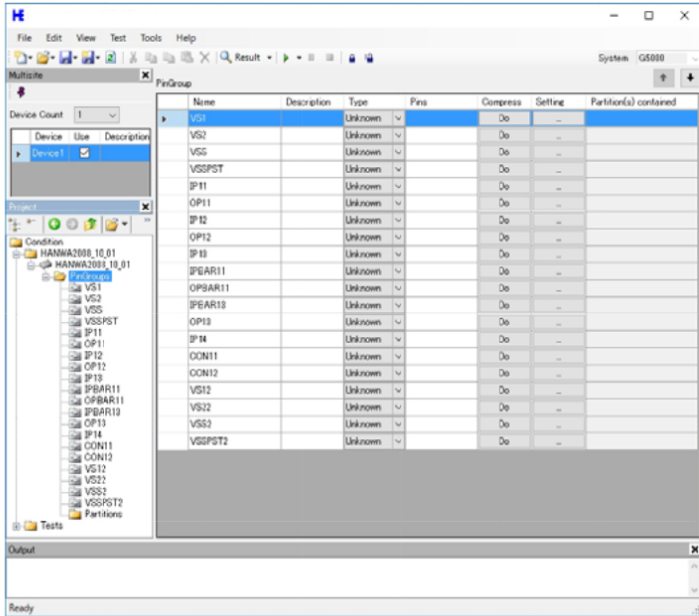
■ Vector (Option)



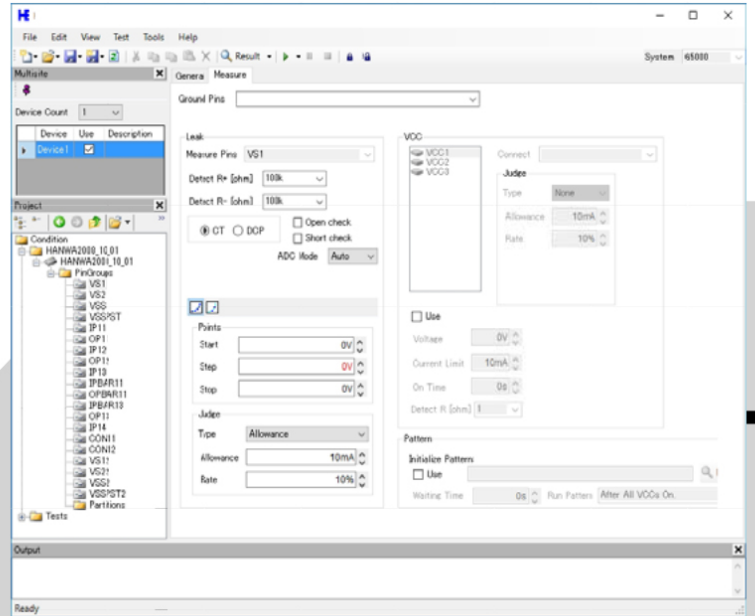
Setting of ESD test and result of the measurement

Setting conditions of system that meets test device, setting conditions of test model, conditions of pulse zapping, etc. are performed easily and speedy. All of these can be saved on local disk.

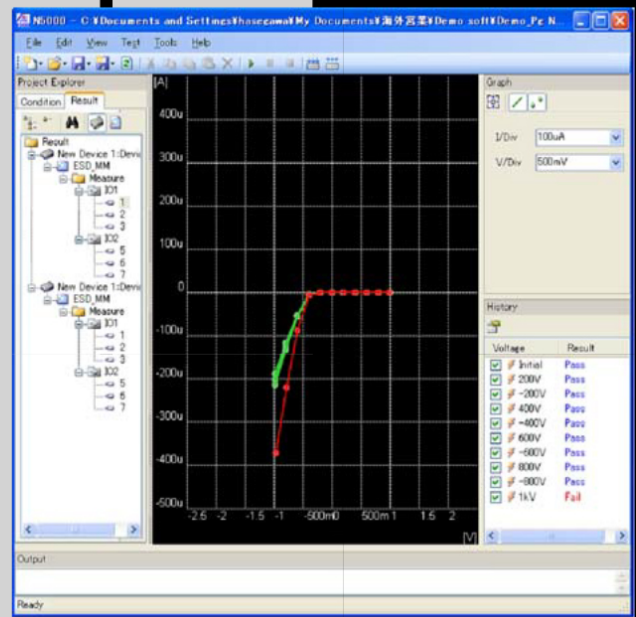
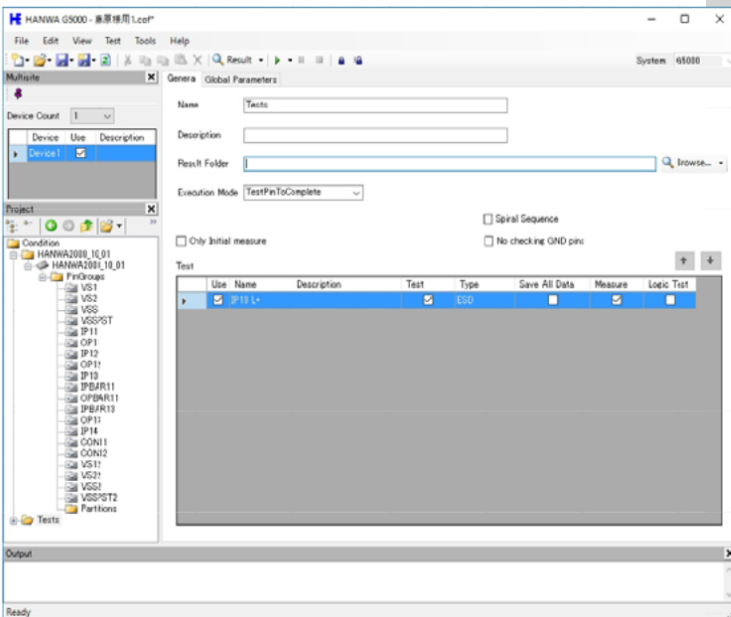
Pin group setting



Measurement conditions of Leakage



Test plan setting



The configuration and function of system

The equipment provides you the choice of test pin number:256 pins, 512 pins, 768 pins and 1024 pins.

※ 2/3 signifies DC power supply for bias. 2 represents 2 power supply type, 3 represents 3 power supply.

Model	Test pin number	ESD Test	Latch-up test (Option)
HED-N5256-D2/6	256 pins	<Support for standards> Corresponds with JEITA , JEDEC, ESDA, AEC <Test model> MM(200PF, 0Ω)×2 HBM(100PF,1500Ω)×2 are featured as standard.	<Support for standards> Corresponds with JEITA , JEDEC, AEC <Test model> ESD Latch-up test (200PF, 0Ω) Constant current Latch-up test Vsupply over-voltage test
HED-N5512-D2/6	512 pins		
HED-N5768-D2/6	768 pins		
HED-N51024-D2/6	1024 pins		

Specification

Equipment model	HED-N5256-D2/6, HED-N5512-D2/6, HED-N5768-D2/6, HED-N51024-D2/6
Capacity of power supply	256 and 512 pins - 100VA, 768 and 1024 pins - 200VA
Pin number of max. measurement	256 pins, 512 pins, 768 pins, 1024 pins
Pulse zapping unit	MM×2, HBM×2 are featured as standard
Pulse voltage	MM:0~±4000V, HBM:0~±8000V
Pulse voltage step	±5V
Pulse zapping number	1~99 times
Pulse interval	0.1~9.9s
Accuracy of charge voltage	1%±10V
Bias DC power supply	±35V/1A (Option available)
Vsupply over-voltage power (for Latch-up test)	100V(1V step)
Vf/Im measurement power supply	±40V (0.1V step) / 100 mA (Option available)
Accuracy of Vf/Im measurement	1%±(1/500FS±10nA)
Pulse current supply	±1A(1mA step)
Wave form sampling (for Latch-up test)	10MHz, Max.4000 points
Destruction judgement	Changing amount judgement / Absolute value judgement Vector (Option)
Outer dimensions	1600(W)×900(D)×1500(H)
Weight	150 Kg~200 Kg
Basic software(OS)	Windows